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Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

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Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China







MOS FET

FCAB21350L1

Panasonic

FCAB21350L1

Gate resistor installed Dual N-channel MOS FET

For lithium-ion secondary battery protection circuits

■ Features

- Low source-source ON resistance:Rss(on) typ. = 2.2 mΩ(VGS = 3.8 V)
- CSP(Chip Size Package)
- RoHS compliant (EU RoHS / MSL:Level 1 compliant)
- Marking Symbol: 3M

■ Packaging

Embossed type (Thermo-compression sealing): 1 000 pcs / reel (standard)

■ Absolute Maximum Ratings Ta = 25 °C

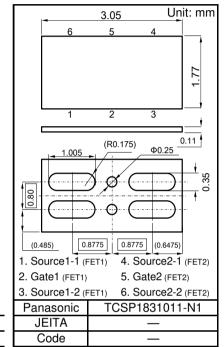
Parameter		Symbol	Rating	Unit	
Source-source Voltage		VSS	12	V	
Gate-source Voltage		VGS	±8	V	
Source Current	DC *1	IS1	12	Α	
	DC *2	IS2	27	Α	
	Pulse *3	ISp	120	Α	
Total Power Dissipation	DC *1	PD1	0.45	W	
Total Fower Dissipation	DC *2	PD2	2.1	W	
Channel Temperature		Tch	150	°C	
Storage Temperature Range		Tstg	-55 to +150	°C	
Thermal Resistance (ch-a)	DC *1	Rth1	278	°C/W	
	DC *2	Rth2	59	°C/W	

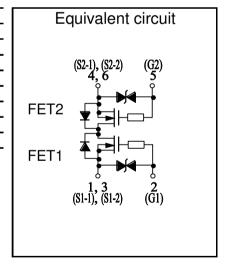
- Note *1 Mounted on FR4 board (25.4 mm \times 25.4 mm \times t1.0 mm) using the minimum recommended pad size (36 μ m Copper).
 - *2 Mounted on Ceramic substrate (70 mm \times 70 mm \times t1.0 mm).

Established: 2015-10-23

Revised

:####-##-##





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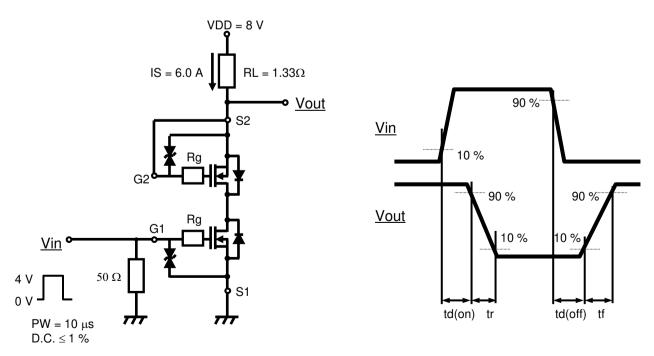
■ Electrical Characteristics Ta = 25 °C ± 3 °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit	
Source-source Breakdown Voltage	VSSS	IS = 1 mA, VGS = 0 V	12			V	
Zero Gate Voltage Source Current	ISSS	VSS = 12 V, VGS = 0 V			1.0	μΑ	
Gate-source Leakage Current	IGSS	$VGS = \pm 8 \text{ V}, VSS = 0 \text{ V}$			±10		
		$VGS = \pm 5 V$, $VSS = 0 V$			±1.0	μΑ	
Gate-source Threshold Voltage	Vth	IS = 1.41 mA, VSS = 10 V	0.35	0.90	1.40	V	
Source-source On-state Resistance	RSS(on)1	IS = 6.0 A, VGS = 4.5 V	1.55	2.1	2.75		
	RSS(on)2	IS = 6.0 A, VGS = 3.8 V	1.6	2.2	2.85	mΩ	
	RSS(on)3	IS = 6.0 A, VGS = 3.1 V	1.65	2.4	3.95		
	RSS(on)4	IS = 6.0 A, VGS = 2.5 V	1.9	3.1	6.1		
Body Diode Forward Voltage	VF(s-s)	IF = 6.0 A, VGS = 0 V		0.8	1.2	V	
Input Capacitance *1	Ciss			4650		рF	
Output Capacitance *1	Coss	VSS = 10 V, VGS = 0 V, f = 1 KHz		580			
Reverse Transfer Capacitance *1	Crss			530			
Turn-on delay Time *1,*2	td(on)	VDD = 8 V, VGS = 0 to 4.0 V		1.2		μS	
Rise Time *1,*2	tr	IS = 6.0 A		2.3			
Turn-off delay Time *1,*2	td(off)	VDD = 8 V, VGS = 4.0 to 0 V		9		μS	
Fall Time *1,*2	tf	IS = 6.0 A		5.0			
Total Gate Charge *1	Qg	VDD = 8 V		43			
Gate-source Charge *1	Qgs	VGS = 0 to 4.0 V,		10		nC	
Gate-drain Charge *1	Qgd	IS = 6.0 A		10			

Note Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.

- *1 Guaranteed by design, not subject to production testing
- *2 Measurement circuit for Turn-on Delay Time / Rise Time / Turn-off Delay Time / Fall Time

Note2: Measurement circuit



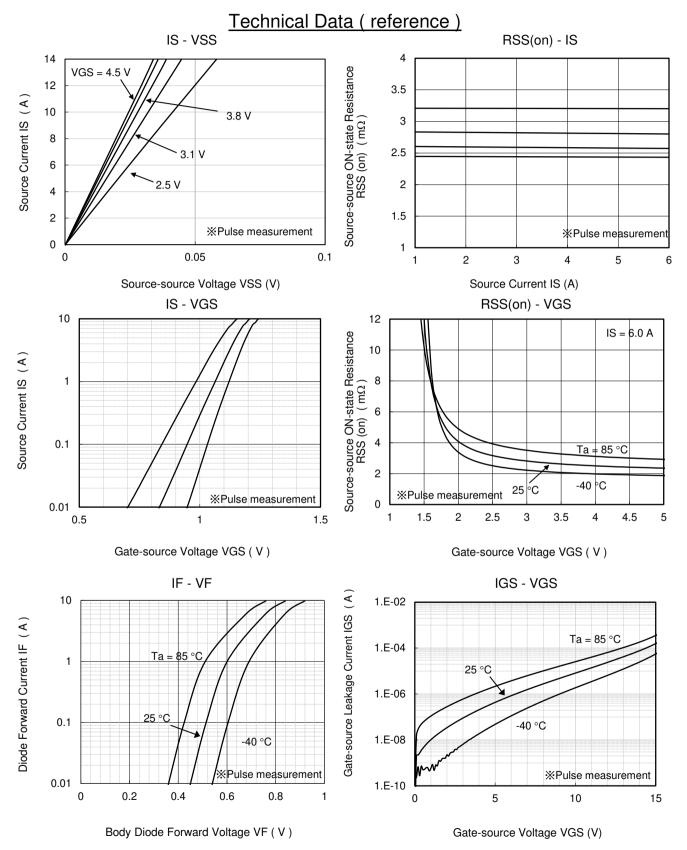
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Technical Data (reference) Zero Gate Voltage Source Current ISS (A) ISS - VSS Dynamic Input/Output Characteristics 1.E-03 Gate - source Voltage VGS (V) VDD = 8 V 1.E-04 IS = 6.0A 4.0 1.E-05 Ta = 85 °C 1.E-06 3.0 1.E-07 2.0 25 °C 1.E-08 1.0 1.E-09 -40 °C 0.0 1.E-10 0 20 30 50 60 70 10 40 5 10 20 Source-source Voltage VSS (V) Gate Charge (nC) Rth - tsw Safe Operating Area 1000 1000 Thermal Resistance Rth (°C/W) limited by RDS(on) (VGS = 3.8 V)PW = 10 μs 100 100 Source Current IS (A) 500 μs 1 ms 10 10 3 ms 11 ms 1 1 Ta = 25 °C. Mounted on FR4 board (25.4 mm ×25.4 mm × t1.0 mm) using the minimum recommended 100 ms 0.1 Mounted on FR4 board (25.4 mm ×25.4 mm × t1.0 mm) using the minimum recommended pad size (36μm Copper s 0.01 0.00010.001 0.01 0.1 100 0.1 10 100 1000 10 Pulse Width tsw (s) Source-source Voltage VSS (V) Normalized Effective Transient Thermal Impedance Thermal Response 10 Ta = 25 °C, Mounted on FR4 board (25.4 mm \times 25.4 mm \times t1.0 mm) using the minimum recommended pad size (36µm Copper) Duty Cycle = 0.5 0.1 0.02

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0.01

0.001

Single Pulse

0.01

0.1

Square Wave Pulse Duration (s)

10

100

1000

0.0001 0.001

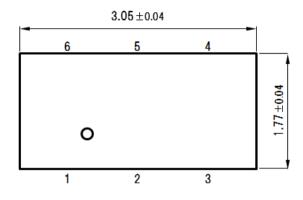
Panasonic

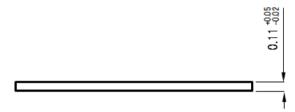
MOS FET

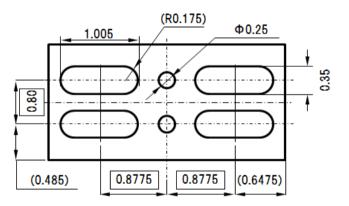
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■ Outline (TCSP1831011-N1)

Unit: mm

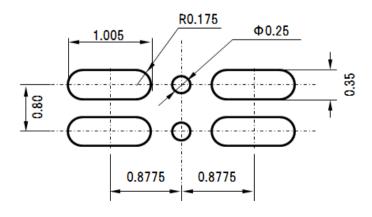






■ Land Pattern (Reference)

Unit: mm



Established: 2015-10-23 Revised

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